Non-negative matrix factorization for isolating damage-free reflections in macromolecular synchrotron data collection

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The damage-free set of reflections in macromolecular crystallography were mathematically isolated by non-negative matrix factorization (NMF). Biological samples undergoing X-ray induced damage under synchrotron X-ray radiation impose a fundamental limit in data collection for crystallography/structural biology [1]. Damage during diffraction data collection can have a significant impact on the quality of the recovered protein structures. Here, we recovered the native X-ray diffraction pattern of tetragonal lysozyme prior to X-ray exposure. NMF has enabled identification of multiple sequential perturbations and isolated the corresponding changes in the reflections from each. NMF is a matrix factorization method that can extract scattered and significant features from large high-dimensional datasets [2]. In NMF, the entire set of dosevarying reflections are cast in a matrix-form as a product of two non-negative matrices, describing the correlated sets of reflections and amplitudes of a small number of pure components. The findings indicate that the unperturbed protein transitions rapidly into multiple sequential components with X-ray exposure corresponding to a dose of 20 MGy under cryogenic conditions. At room temperature, NMF enabled independent isolation of perturbations to the reflections from direct X-ray exposure versus diffusion of molecular radicals generated upon solvent exposure. During room temperature X-ray data collection, the crystals are damaged faster than cryogenic conditions. Application of NMF during the damage mechanism helps in observing the firsthand effects of indirect X-ray radiation around the sample.

References

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